

Search Notes

Application/Control No.

10/540,157

Examiner

HANH N. NGUYEN

Applicant(s)/Patent under
Reexamination

TOIDE ET AL.

Art Unit

2834

SEARCHED

Class	Subclass	Date	Examiner
310	216	1/31/2008	HN
310	254	1/31/2008	HN
H02K	21/00	1/31/2008	HN
H02K	5/18	1/31/2008	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR